FUJITSU SEMICONDUCTOR DATA SHEET

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DS05-13101-3E

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## Memory FRAM

**CMOS** 

# 256 K (32 K × 8) Bit

# **MB85R256**

#### DESCRIPTIONS

The MB85R256 is an FRAM (Ferroelectric Random Access Memory) chip in a configuration of 32,768 words x 8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells.

Unlike SRAM MB85R256 is able to retain data without back-up battery.

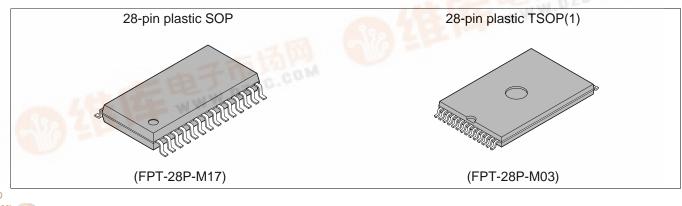
The memory cells used for the MB85R256 has inproved at least 10<sup>10</sup> times of read/write access per bit, significantly outperforming FLASH memory and EEPROM in durability.

The MB85R256 uses a pseudo - SRAM interface compatible with conventional asynchronous SRAM. WWW.DZSC.

#### FEATURES

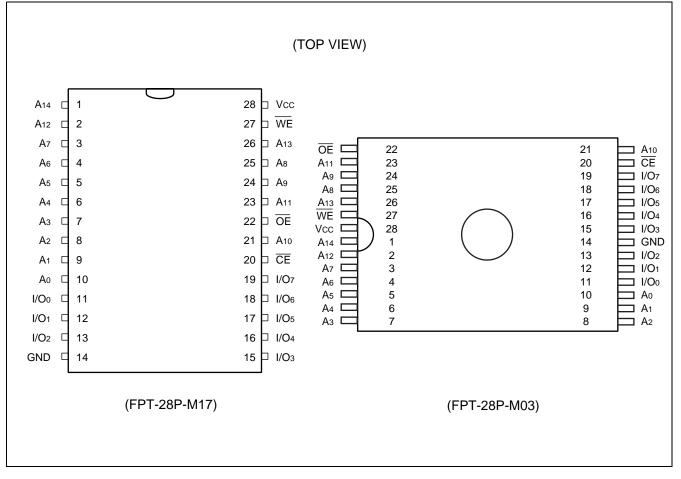
- Bit configuration: 32,768 words x 8 bits
- Read/write durability: 10<sup>10</sup> times/bit (Min)
- Peripheral circuit CMOS construction
- Operating power supply voltage: 3.0 V to 3.6 V
- Operating temperature range: -40 °C to +85 °C
- 28-pin, SOP flat package
- 28-pin, TSOP(1) flat package

#### PACKAGES





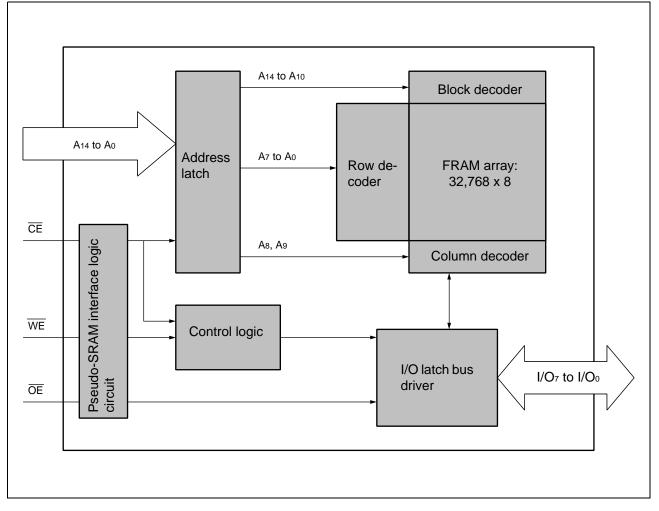
#### ■ PIN ASSIGNMENTS



#### ■ PIN DESCRIPTIONS

Pin name	Function
A <sub>0</sub> to A <sub>14</sub>	Address Input
I/O <sub>0</sub> to I/O <sub>7</sub>	Data input/output
CE	Chip enable input
WE	Write Enable input
ŌĒ	Output enable input
Vcc	Power supply ( + 3.3 V Typ)
GND	Ground

#### ■ BLOCK DIAGRAM



#### ■ FUNCTION LIST

Operation mode	CE	WE	OE	I/O7 to I/O0	Power supply current
Standby precharge	Н	×	×	High-Z	Standby
Standby precharge	×	L	L	Tign-2	(Isв)
Latch address	L	Ţ	Ţ	—	—
Write	L	L	Н	Data input	
Read	L	н	L	Data output	Operation (Icc)
Output Disable	×	Н	Н	High-Z	

H: High level, L: Low level, x: Irrespective of "H" or "L"

Parameter	Symbol	Ra	Unit	
Farameter	Symbol	Min	Мах	Unit
Power supply voltage	Vcc	- 0.5	+ 4.6	V
Input voltage	Vin	- 0.5	Vcc + 0.5	V
Output voltage	Vout	- 0.5	Vcc + 0.5	V
Operating temperature	TA	- 40	+ 85	°C
Storage temperature	Tstg	- 40	+ 85	°C

#### ■ ABSOLUTE MAXIMUM RANGES

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

#### RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol		Unit		
Falameter	Symbol	Min	Тур	Max	Unit
Power supply voltage	Vcc	3.0	3.3	3.6	V
High level input voltage	Vih	0.8  imes Vcc		Vcc + 0.5	V
Low level input voltage	Vı∟	- 0.5		+ 0.6	V
Operating temperature	TA	- 40		+ 85	°C

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

#### ELECTRICAL CHARACTERISTICS

#### 1. DC Characteristics

(within recommended operating conditions)

Parameter	Symbol	Conditions		Value		Unit
Farameter	Symbol	Conditions	Min	Тур	Max	Unit
Input leakage current	<b>I</b> u	$V_{IN} = 0 V to V_{CC}$			10	μΑ
Output leakage current	Ilo	$\frac{V_{OUT} = 0 V \text{ to } V_{CC},}{\overline{CE} = V_{IH} \text{ or } \overline{OE} = V_{IH}}$		_	10	μΑ
Operating power supply current	lcc	$\label{eq:cell} \begin{split} \overline{CE} &= 0.2 \ V, \\ Other \ Inputs &= V_{CC} - 0.2 \ V/0.2 \ V, \\ t_{RC} \ (Min), \ Ii/o &= 0 \ mA \end{split}$		5	10	mA
Standby current	lsв	<u>CE</u> ≥ Vcc		5	100	μA
High level output voltage	Vон	Іон = - 100 μА	0.8  imes Vcc	_	_	V
Low level output voltage	Vol	IoL = 1.0 mA	_		0.4	V

#### 2. AC Characteristics

#### (1) Read cycle

				0
Parameter	Symbol	Va	lue	Unit
	Symbol	Min	Max	Unit
Read cycle time	trc	235		
CE active time	tcA	150	10,000	
Read pulse width	t <sub>RP</sub>	150	10,000	
Precharge time	tPC	85	—	
Address setup time	tas	0		20
Address hold time	tан	25	—	ns
CE access time	tce		150	
OE access time	toe		150	
CE output floating time	tнz		25	
OE output floating time	tонz		25	

(within recommended operating conditions)

#### (2) Write cycle

(within recommended operating conditions)							
Parameter	Symbol	Va	lue	Unit			
Farameter	Symbol –	Min	Мах	Unit			
Write cycle time	twc	235	—				
CE active time	tca	150	10,000				
Write pulse width	twp	150	10,000				
Precharge time	tec	85	—				
Address setup time	tas	0		20			
Address hold time	tан	25		ns			
Data setup time	tos	50	—				
Data hold time	tон	0	—				
Write set up time	tws	0					
Write hold time	twн	0					

#### (3) Power ON/OFF sequence

(within recommended operating conditions)

Parameter	Symbol		Unit		
Farameter	Symbol	Min	Тур	Max	Onit
CE LEVEL hold time at power OFF	tpd	85			ns
CE LEVEL hold time at power ON	tpu	85			ns
Power interval	tpi	1		_	μs

#### 3. Pin Capacitance

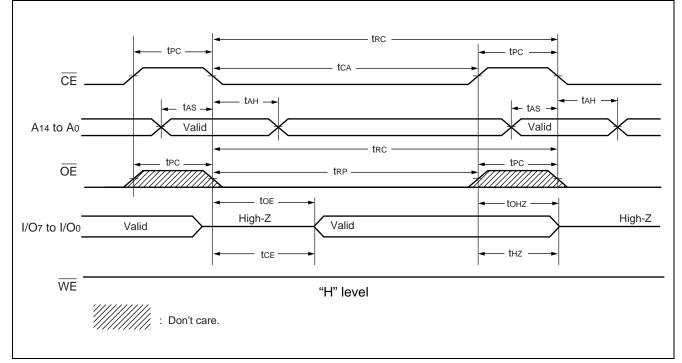
Parameter	Symbol	Conditions		Value		Unit
Farameter	Symbol	Conditions	Min	Тур	Max	Unit
Input capacitance	CIN	$V_{IN} = V_{OUT} = GND,$		—	10	pF
output capacitance	Соит	$f = 1 \text{ MHz}, T_A = +25 \text{ °C}$		—	10	pF

#### 4. AC Characteristics Test Condition

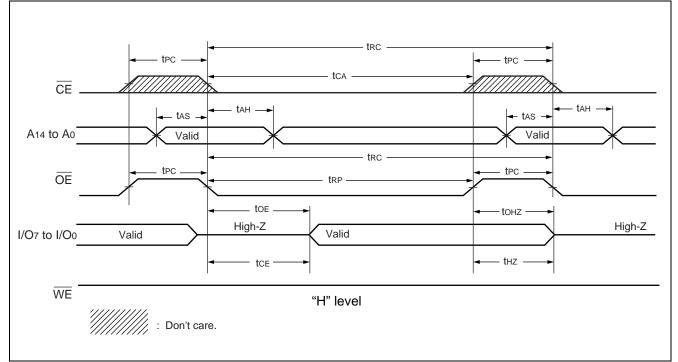
Power supply voltage	: 3.0 V to 3.6 V
Input voltage amplitude	: 0.3 V to 2.7 V
Input rising time	: 10 ns
Input falling time	: 10 ns
Input evaluation level	: 2.0 V/0.8 V
Output evaluation level	: 2.0 V/0.8 V
Output load	: 100 pF

#### TIMING DIAGRAM

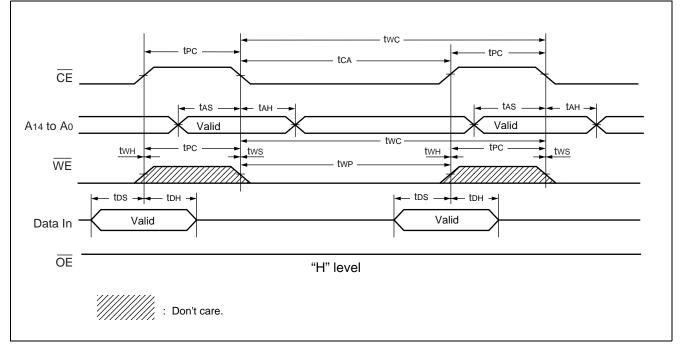
#### 1. Read cycle (CE Control)



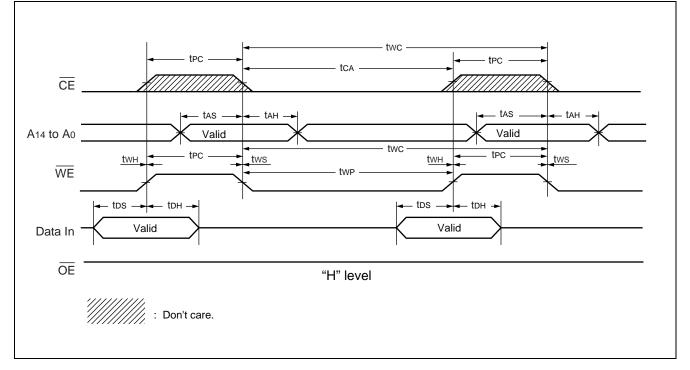
#### 2. Read cycle (OE Control)



#### 3. Write cycle (CE Control)



#### 4. Write cycle (WE Control)



#### ■ POWER ON/OFF SEQUENCE – tpi 🔶 tpd -– tpu – • • Vcc - Vcc 3.0 V ..... 3.0 V Viн (Min) Vін (Min) 1.0 V -- 1.0 V Vı∟ (Max) Vı∟ (Max) ---- 0.2 V GND 0.2 V GND $\overline{\text{CE}} > \text{Vcc} \times 0.8^{*}$ CE : Don't Care $\overline{\text{CE}} > \text{Vcc} \times 0.8^*$ CE CE \* : <u>CE</u> (Max) < Vcc + 0.5 V

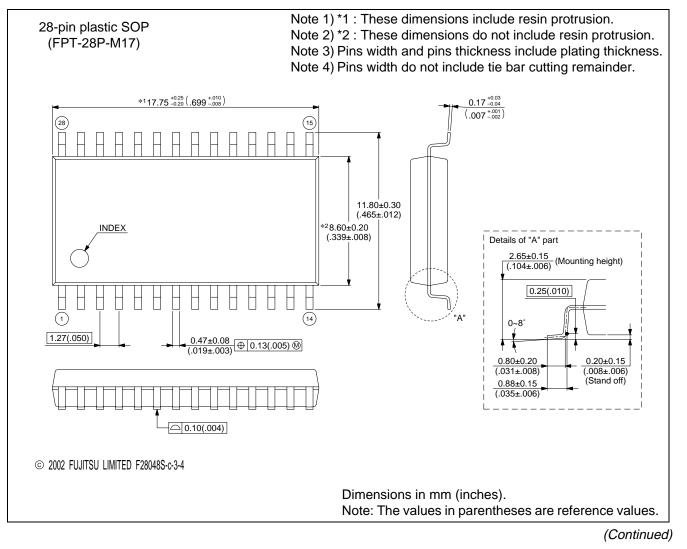
### ■ NOTES ON USE

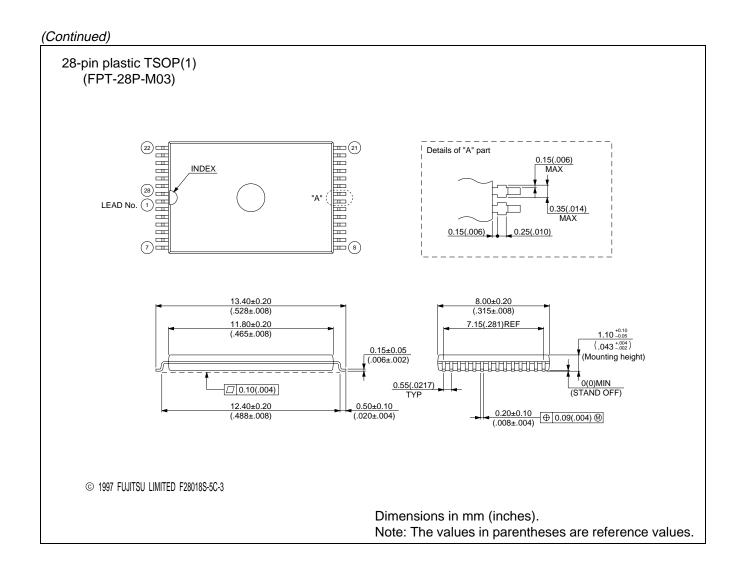
After IR reflow, the hold of data that was written before IR reflow is not guaranteed.

#### ORDERING INFORMATION

Part number	Package	Remarks
MB85R256PF	28-pin, plastic SOP (FPT-28P-M17)	
MB85R256PFTN	28-pin, plastic TSOP(1) (FPT-28P-M03)	

#### PACKAGE DIMENSIONS





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